Notice of References Cited Application/Control No. 10/740,465 Examiner Seokyun Moon Applicant(s)/Patent Under Reexamination BAEK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,362,804	03-2002	Park et al.	345/99
*	В	US-6,721,009	04-2004	lizuka, Tetsuya	348/314
	С	US-			
	D	US-			
	E	US-			
	F	US-		·	
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	T	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	*				
	0			•		
	Р		3 00 0			
	α					
	R	•				
	S					
	Т					

NON-PATENT DOCUMENTS

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U		·				
	V						
	w ·						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.